



P-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}$ (Ω)	$I_D(A)^{a, e}$ $Q_g(Ty)$				
- 30	0.045 at V _{GS} = - 10 V	- 5.9	7 nC			
	0.075 at V _{GS} = - 4.5 V	- 4.6	7 110			

TO-236 (SOT-23) G 1 Top View Si2343CDS (P1)* * Marking Code

Ordering Information: Si2343CDS-T1-GE3 (Lead (Pb)-free and Halogen-free)

FEATURES

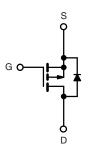
- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET® Power MOSFET
- 100 % R_g Tested
- Compliant to RoHS Directive 2002/95/EC



HALOGEN FREE

APPLICATIONS

- Load Switch
- Notebook Adaptor Switch
- DC/DC Converter



P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T _A = 25 °C, unless otherwise noted					
Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	- 30	V	
Gate-Source Voltage		V_{GS}	± 20		
	T _C = 25 °C		- 5.9		
Continuous Drain Current /T 150 °C)	T _C = 70 °C	- I _D	- 4.7		
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C		- 4.2 ^{b, c}		
	T _A = 70 °C		- 3.3 ^{b, c}	Α	
Pulsed Drain Current		I _{DM}	- 25	-	
Continous Source-Drain Diode Current	T _C = 25 °C		- 2.1		
	T _A = 25 °C	- I _S	- 1 ^{b, c}		
Maximum Power Dissipation	T _C = 25 °C	P _D	2.5		
	T _C = 70 °C		1.6	w	
	T _A = 25 °C		1.25 ^{b, c}		
	T _A = 70 °C		0.8 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 5 s	R _{thJA}	75	100	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	40	50		

Notes:

- a. Based on $T_C = 25$ °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 5 s.
- d. Maximum under Steady State conditions is 166 $^{\circ}\text{C/W}.$
- e. Package Limited.

Si2343CDS

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Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I - 250 uA		- 19		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			4.4			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_{D} = -250 \mu A$	- 1.2		- 2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = - 30 V, V _{GS} = 0 V			- 1	μА	
		$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			- 5		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \le -5 \text{ V}, V_{GS} = -10 \text{ V}$	- 25			Α	
		V _{GS} = - 10 V, I _D = - 4.2 A		0.037	0.045	Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 3.2 A		0.062	0.075		
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 4.2 A		10		S	
Dynamic ^b							
Input Capacitance	C _{iss}			590		pF	
Output Capacitance	C _{oss}	V _{DS} = - 15 V, V _{GS} = 0 V, f = 1 MHz		115			
Reverse Transfer Capacitance	C _{rss}	1		93			
Total Oats Observe	Qg	V _{DS} = -15 V, V _{GS} = -10 V, I _D = -4.2 A		13.6	21	nC	
Total Gate Charge				7	11		
Gate-Source Charge	Q_{gs}	V _{DS} = - 15 V, V _{GS} = - 4.5 V, I _D = - 4.2 A		2.3			
Gate-Drain Charge	Q_{gd}			3.2			
Gate Resistance	R_g	f = 1 MHz	1	5	10	Ω	
Turn-On Delay Time	t _{d(on)}			30	45	-	
Rise Time	t _r	$V_{DD} = -15 \text{ V}, R_{L} = 4.5 \Omega$		25	38		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 3.3 A, V_{GEN} = - 4.5 V, R_g = 1 Ω		16	24		
Fall Time	t _f]		8	16		
Turn-On Delay Time	t _{d(on)}			8	16	ns	
Rise Time	t _r	$V_{DD} = -15 \text{ V}, R_{L} = 4.5 \Omega$		10	20	1	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 3.3 A, V_{GEN} = - 10 V, R_g = 1 Ω		18	27		
Fall Time	t _f			8	16		
Drain-Source Body Diode Characteristic	cs						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			- 4.2	A	
Pulse Diode Forward Current	I _{SM}				- 25		
Body Diode Voltage	V_{SD}	I _S = - 3.3 A, V _{GS} = 0 V		- 0.8	- 1.2	V	
Body Diode Reverse Recovery Time	t _{rr}	I _F = - 3.3 A, dl/dt = 100 A/μs, T _J = 25 °C		17	26	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			9	18	nC	
Reverse Recovery Fall Time	t _a			10			
Reverse Recovery Rise Time	t _b	1		7		ns	

Notes:

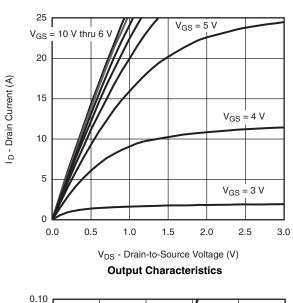
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

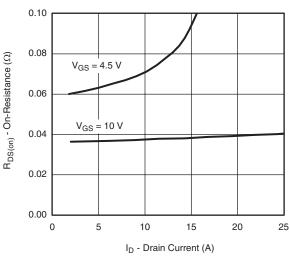
a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

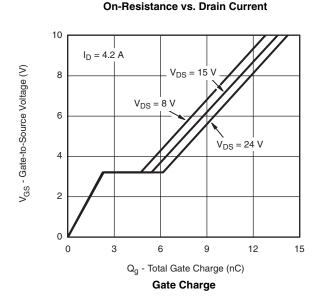
b. Guaranteed by design, not subject to production testing.

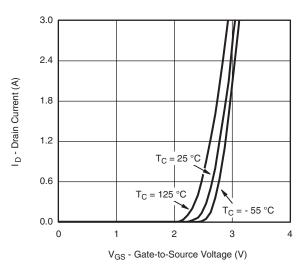


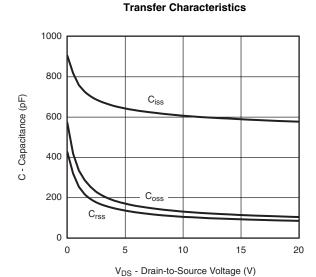
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

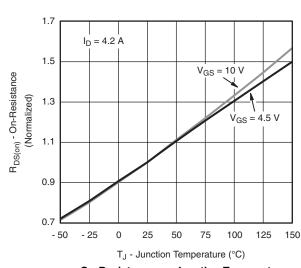












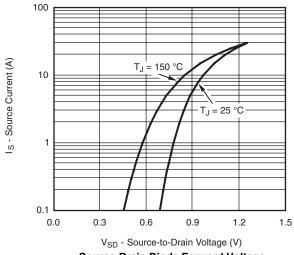
Capacitance

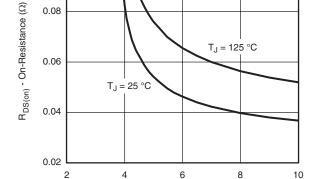
On-Resistance vs. Junction Temperature

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 $I_D = 4.2 A$

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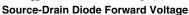


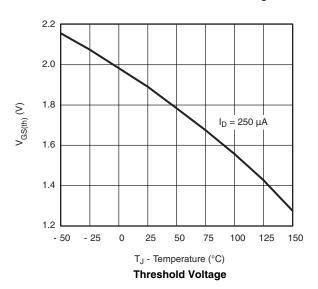


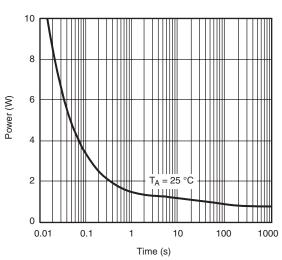
0.10

0.08

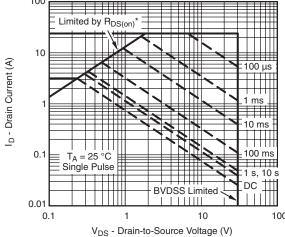
V_{GS} - Gate-to-Source Voltage (V) On-Resistance vs. Gate-to-Source Voltage







Single Pulse Power (Junction-to-Ambient)

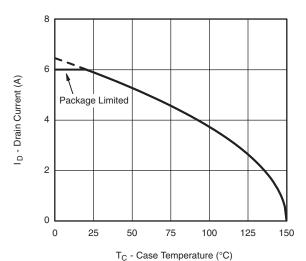


* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

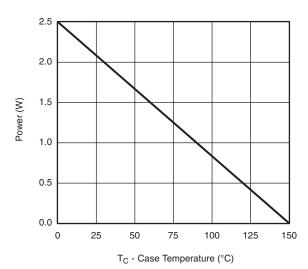
Safe Operating Area, Junction-to-Ambient

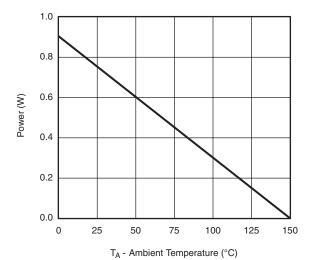


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Current Derating*





Power, Junction-to-Foot

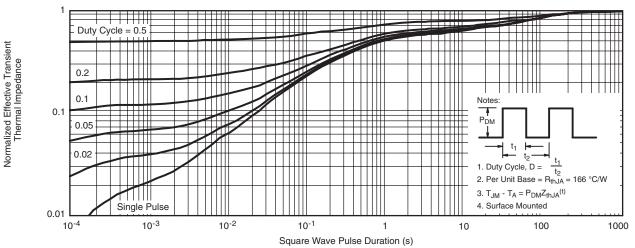
Power, Junction-to-Ambient

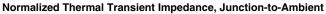
 $^{^{\}star}$ The power dissipation P_D is based on T_{J(max)} = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

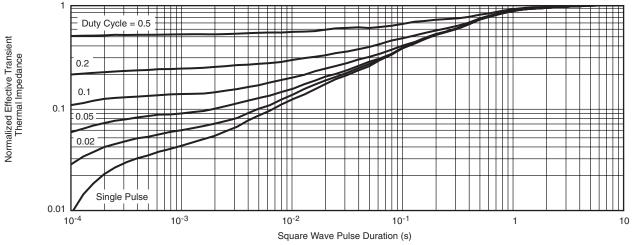
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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted







Normalized Thermal Transient Impedance, Junction-to-Foot

Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see www.vishay.com/ppq?65474.



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